

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination TANNER ET AL.	
		Examiner SHEWAYE GELAGAY	Art Unit 2137	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0107691	08-2002	Kirovski et al.	704/270
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
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	J	US-			
	K	US-			
	L	US-			
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**FOREIGN PATENT DOCUMENTS**

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	N					
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	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Felten et al. "Reading Between the Lines: Lessons from the SDMI Challenge" USENIX, August 13-17, 2001
	V	Cox et al. "Some general methods for tampering with watermarks" IEEE , 1998, pages 1-15
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.